Reliability data supporting the release of the ADM3485E fabricated on 1um HV CMOS process at TSMC

Test	Conditions	Sample Size	Results
High Temperature Operating Life (HTOL)*	JEDEC-STD-22-Method A108	3*45	Pass
High Temperature Operating Life (HTOL)*	JEDEC-STD-22-Method A108	1*72	Pass
High Temperature Operating Life (HTOL)*	JEDEC-STD-22-Method A108	1*32	Pass
High Temperature Operating Life (HTOL)*	JEDEC-STD-22-Method A108	3*50	Pass
High Temperature Operating Life (HTOL)	JEDEC-STD-22-Method A108	1*77	Pass
Highly Accelerated Stress Test (HAST)*	JEDEC-STD-22-Method A110	3*77	Pass
Highly Accelerated Stress Test (HAST)*	JEDEC-STD-22-Method A110	3*45	Pass
Highly Accelerated Stress Test (HAST)*	JEDEC-STD-22-Method A110	2*45	Pass
Highly Accelerated Stress Test (HAST)*	JEDEC-STD-22-Method A110	1*25	Pass
Early Life Failure (ELF)	MIL-STD-883, Method 1015	1*717	Pass
Early Life Failure (ELF)	MIL-STD-883, Method 1015	1*790	Pass
Early Life Failure (ELF)	MIL-STD-883, Method 1015	1*1010	Pass
Early Life Failure (ELF)	MIL-STD-883, Method 1015	1*1007	Pass
High Temperature Storage Life (HTSL)	JESD22-A103	2*77	Pass
High Temperature Storage Life (HTSL)	JESD22-A103	1*77	Pass
High Temperature Storage Life (HTSL)	JESD22-A103	2*77	Pass
High Temperature Storage Life (HTSL)	JESD22-A103	1*45	Pass
High Temperature Storage Life (HTSL)	JESD22-A103	1*77	Pass
Latch-Up	JEDEC Standard 78	-	Pass
Electrostatic Discharge *Human Body Model*	JESD22-A114	-	Pass
Electrostatic Discharge *Field-Induced Charged Device Model*	JESD22-C101	-	Pass
Electrostatic Discharge, 15kV IEC	IEC 1000-4-2	-	Pass

*Units preconditioned Per JEDEC/IPC J-STD-020